

Notice of References Cited

Application/Control No.

10/598,804

Applicant(s)/Patent Under
Reexamination
KATOH ET AL.

Examiner

Alexander O. Williams

Art Unit

2826

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,445,039	09-2002	Woo et al.	257/355
*	B	US-2007/0091521 A1	04-2007	Hsueh et al.	361/056
*	C	US-2006/0232898 A1	10-2006	Morishita, Yasuyuki	361/056
*	D	US-2005/0253236 A1	11-2005	Nakayama, Akimoto	257/678
*	E	US-2005/0151160 A1	07-2005	Salcedo et al.	257/173
*	F	US-2005/0122646 A1	06-2005	Okushima, Mototsugu	361/056
*	G	US-2005/0035416 A1	02-2005	Kuroda et al.	257/401
*	H	US-2004/0207079 A1	10-2004	Matsumoto, Shuuji	257/724
*	I	US-2004/0012065 A1	01-2004	Shiina, Masahiro	257/459
*	J	US-2001/0024348 A1	09-2001	May et al.	361/56
*	K	US-6,518,608 B1	02-2003	Takizawa, Noboru	257/256
*	L	US-6,078,068	06-2000	Tamura, Ronald Kazuo	257/203
*	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.